Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/813,782	MITA, KIYOSHI	
Examiner	Art Unit	
Chris C. Chu	2815	

SEARCHED						
Class	Subclass	Date	Examiner			
257	E21.505, 678, 774 and 772	9/25/2006	C.C.			
		-"				

INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
	<u> </u>				

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
Searched in US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; FPRS; and IBM_TDB;	9/25/2006	C.C.		